

April 1999

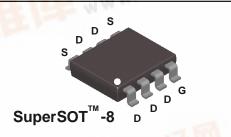
### FDR836P P-Channel 2.5V Specified MOSFET

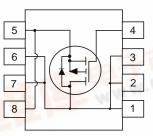
### **General Description**

SuperSOT<sup>TM</sup> -8 P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as battery powered circuits or portable electronics where low in-line power loss, fast switching and resistance to transients are needed.

### Features

- -6.1 A, -20 V.  $R_{DS(ON)} = 0.030$  W @  $V_{GS} = -4.5$  V  $R_{DS(ON)} = 0.040$  W @  $V_{GS} = -2.5$  V
- High density cell design for extremely low R<sub>DS(ON)</sub>.
- Small footprint (38% smaller than a standard SO-8); low profile package (1 mm thick); power handling capability similar to SO-8.





### Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

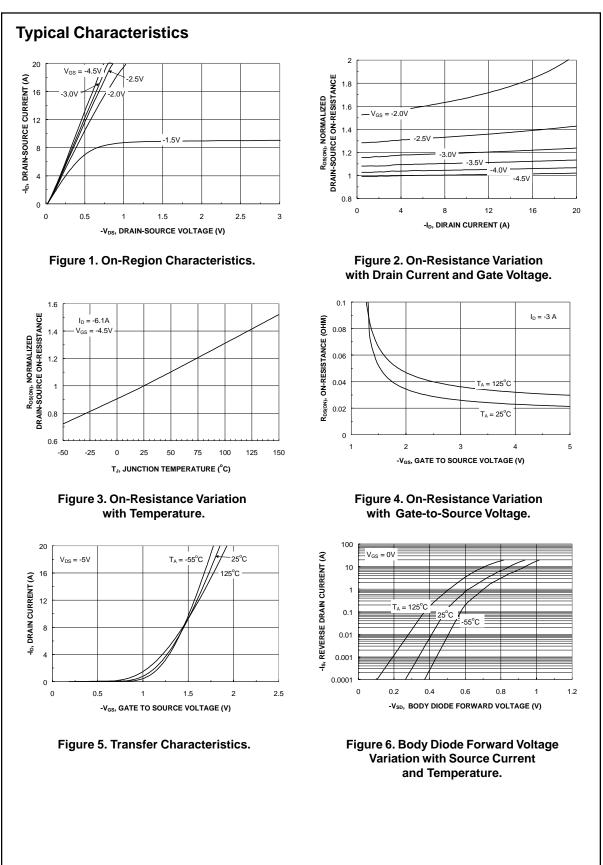
Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage		<u>+</u> 8	V
l <sub>D</sub>	Drain Current - Continuous	(Note 1a)	-6.1	A
	- Pulsed		-18	Lec.
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	1.8	W
		(Note 1b)	1.0	
		(Note 1c)	0.9	
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Junction Temperature Range		-55 to +150	۰C

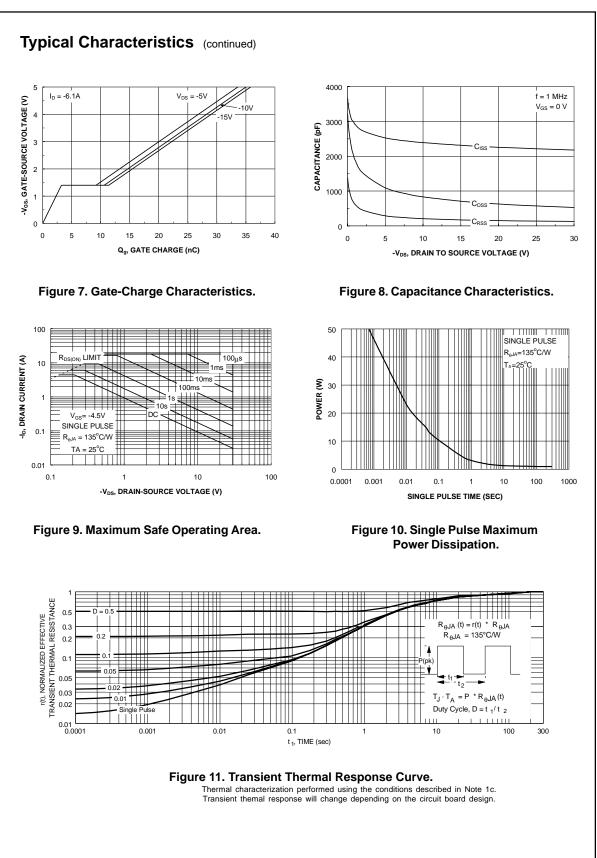
### Thermal Characteristics R<sub>θJA</sub> Thermal Resistance, Junction-to-Ambient (Note 1a) 70 °C/W R<sub>θJC</sub> Thermal Resistance, Junction-to-Case (Note 1) 20 °C/W

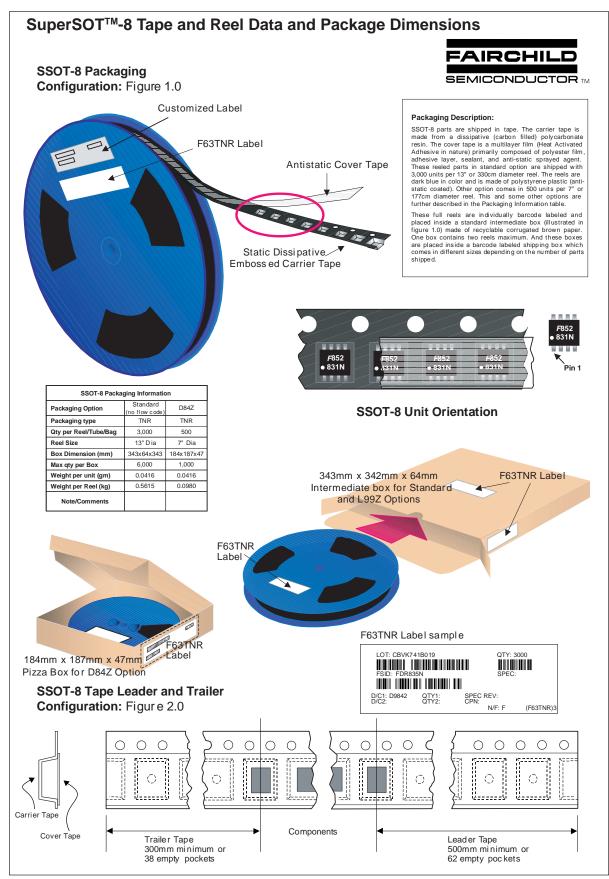
### Package Outlines and Ordering Information

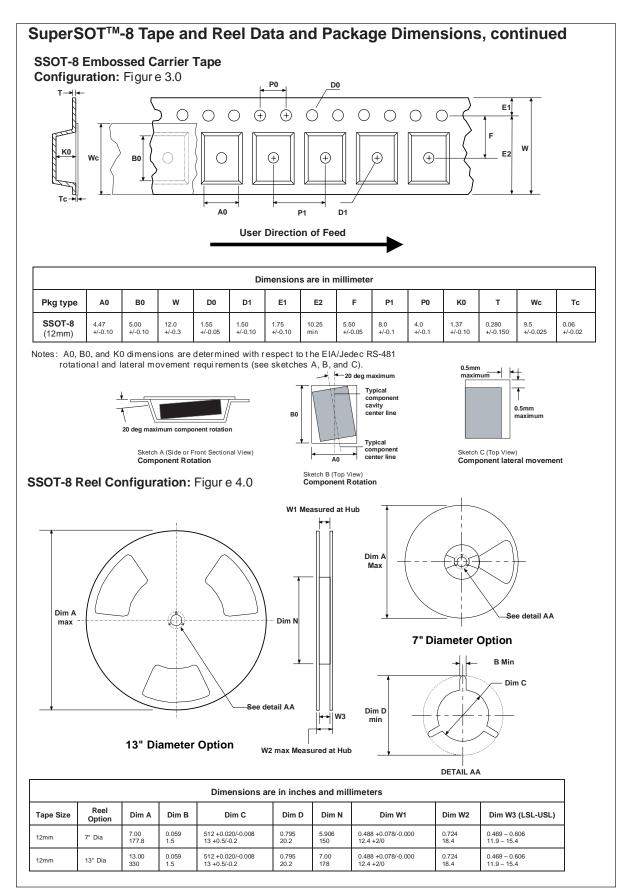
Device Marking	Device	Reel Size	Tape Width	Quantity
.836P	FDR836P	13"	12mm	3000 units

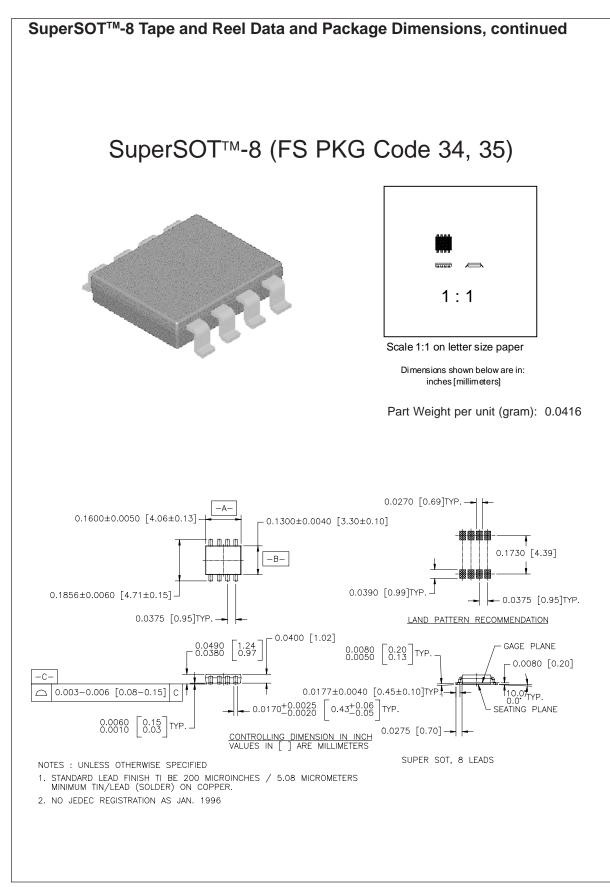
Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
)ff Char	acteristics					
VDSS	Drain-Source Breakdown Voltage	$V_{GS} = 0 V$ , $I_{D} = -250 \mu A$	-20			V
BVbss ATJ	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, Referenced to 25°C		-24		mV/∘C
SS	Zero Gate Voltage Drain Current	$V_{DS} = -16 V, V_{GS} = 0 V$			-1	μA
SSF	Gate-Body Leakage Current, Forward	$V_{GS} = 8 V, V_{DS} = 0 V$			100	nA
SSR	Gate-Body Leakage Current, Reverse	$V_{GS}$ = -8 V, $V_{DS}$ = 0 V			-100	nA
)n Char	acteristics (Note 2)					
GS(th)	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	-0.4	-0.6	-1	V
VGS(th) 	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$ , Referenced to 25°C		3		mV/∘C
DS(on)	Static Drain-Source On-Resistance	$ \begin{array}{l} V_{GS}=-4.5 \ V, \ I_{D}=-6.1 \ A \\ V_{GS}=-4.5 V, \ I_{D}=-6.1 \ A, T_{J}{=}125^{\circ}C \\ V_{GS}=-2.5 \ V, \ I_{D}=-5 \ A \end{array} $		0.022 0.031 0.029	0.030 0.048 0.040	Ω
D(on)	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	-9			Α
FS	Forward Transconductance	$V_{DS} = -5 V, I_{D} = -6.1A$		22		S
Ovnamio	c Characteristics					
iss	Input Capacitance	$V_{DS} = -25 V, V_{GS} = 0 V,$		2200		pF
OSS	Output Capacitance	f = 1.0 MHz		570		pF
rss	Reverse Transfer Capacitance	1		140		pF
Switchin	ng Characteristics (Note 2)					
l(on)	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$		10	18	ns
1(01)	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, \text{ R}_{GEN} = 6 \Omega$		14	25	ns
(off)	Turn-Off Delay Time			225	360	ns
((01))	Turn-Off Fall Time			85	135	ns
) <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -6.1 A,		32	44	nC
) <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = - 4.5 V		3.2		nC
) <sub>gd</sub>	Gate-Drain Charge			8.1		nC
	Diada Characteristica en	d Maximum Datinga				
<u>3 Jrain-50</u>	Durce Diode Characteristics an Maximum Continuous Drain-Source Dio				-1.5	А
/ <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = -1.5 \text{ A}$ (Note 2)		-0.65	-1.2	V
				0.00	=	-
Notes: 1. R <sub>gJA</sub> is the	sum of the junction-to-case and case-to-ambient thermal e drain Pins. $R_{qCA}$ is guaranteed by design while $R_{qCA}$ is	resistance where the case thermal reference is def	ined as the			
	a) 70 °C/W when mounted on a 1.0 in <sup>2</sup> pad of 2 oz. copper.	b) 125°C/W when mounted on a 0.026 in <sup>2</sup> pad of 2oz. copper.		c) 135℃/ minimum	W when mo pad.	unted on











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